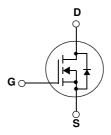
### **Features**

• 0.2 A, 600 V,  $R_{DS(on)}$ =9.3  $\Omega$ (





# **MOSFET Maximum Ratings** $T_C = 25^{\circ}C$ unless otherwise noted\*

Symbol		Parameter		FQT1N60C	Unit	
V <sub>DSS</sub>	Drain to Source Voltage	age		600	V	
V <sub>GSS</sub>	Gate to Source Voltage			±30	V	
ı	Drain Current	-Continuous (T <sub>C</sub> = 25°C)		0.2	۸	
ID	Diamourient	-Continuous (T <sub>C</sub> = 100°C)		0.12	A	
$I_{DM}$	Drain Current	- Pulsed	(Note 1)	0.8	Α	
E <sub>AS</sub>	Single Pulsed Avalanche I	Energy	(Note 2)	33	mJ	
I <sub>AR</sub>	Avalanche Current		(Note 1)	0.2	Α	
E <sub>AR</sub>	Repetitive Avalanche Ene	rgy	(Note 1)	0.2	mJ	
dv/dt	Peak Diode Recovery dv/d	dt	(Note 3)	4.5	V/ns	
D	Dawer Dissipation	$(T_A = 25^{\circ}C)$		2.1	W	
$P_{D}$	Power Dissipation	- Derate above 25°C		0.02	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Te	mperature Range	rature Range		°C	
T <sub>L</sub>	Maximum Lead Temperate 1/8" from Case for 5 Seco	ure for Soldering Purpose, nds		300	°C	

### **Thermal Characteristics**

Symbol	Parameter	Min.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient*	-	60	°C/W

<sup>\*</sup> When mounted on the minimum pad size recommended (PCB Mount)

### Package Marking and Ordering Information $T_C = 25^{\circ}C$ unless otherwise noted

<b>Device Marking</b>	Device	Package	Reel Size	Tape Width	Quantity
FQT1N60C	FQT1N60C	SOT-223	330mm	12mm	4000

### **Electrical Characteristics**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250 \mu A$ , $V_{GS} = 0 V$ , $T_J = 25 ^{\circ} C$	600	-	-	V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C	-	0.6	-	V/°C
	Zero Gate Voltage Drain Current	$V_{DS} = 600V, V_{GS} = 0V$	-	-	25	μА
DSS		$V_{DS} = 480V, T_{C} = 125^{\circ}C$	-	-	250	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 30V, V_{DS} = 0V$	-	-	±100	nA

### **On Characteristics**

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2.0	-	4.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 0.1A$	-	9.3	11.5	Ω
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 40V, I_D = 0.1A$ (Note 4)	-	0.75	-	S

### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 05V V 0V	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V f = 1MHz	-	130	170	pF
C <sub>oss</sub>	Output Capacitance	20		-	19	25	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1101112		-	3.5	6	pF
$Q_g$	Total Gate Charge at 10V			-	4.8	6.2	nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{DS} = 480V, I_{D} = 1A$		-	0.7	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	V <sub>GS</sub> = 10V	(Note 4, 5)	-	2.7	-	nC

### **Switching Characteristics**

$t_{d(on)}$	Turn-On Delay Time		-	7	24	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 300V, I_D = 1A$	-	21	52	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 25\Omega$	-	13	36	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)	-	27	64	ns

### **Drain-Source Diode Characteristics**

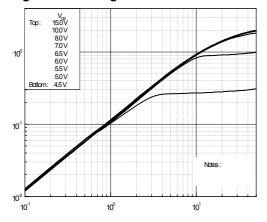
I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current			-	0.2	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	0.8	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0V, I_{SD} = 0.2A$	-	-	1.4	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 1A	-	190	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$ (No	te 4) -	0.53	-	μС

#### Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L = 59mH, I $_{AS}$  = 1.1A, V $_{DD}$  = 50V, R $_{G}$  = 25 $\Omega$ , Starting T $_{J}$  = 25°C
- 3.  $I_{SD} \le 0.2 A$ , di/dt  $\le 200 A/\mu s$ ,  $V_{DD} \le BV_{DSS}$ , Starting  $T_J$  = 25°C
- 4. Pulse Test: Pulse width  $\leq 300 \mu s, \, \text{Duty Cycle} \leq 2\%$
- 5. Essentially Independent of Operating Temperature Typical Characteristics

## **Typical Performance Characteristics**

Figure 1. On-Region Characteristics



**Figure 2. Transfer Characteristics** 

Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

Figure 5. Capacitance Characteristics

Figure 6. Gate Charge Characteristics

## **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

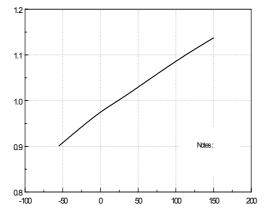


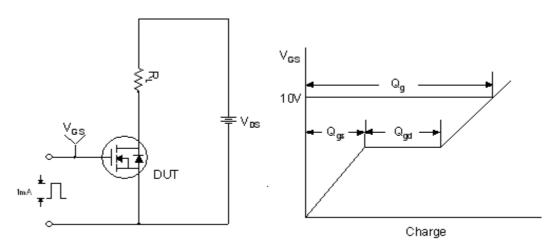
Figure 8. On-Resistance Variation vs. Temperature

Figure 9. Maximum Safe Operating Area

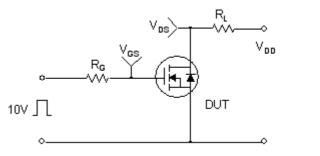
Figure 10. Maximum Drain Current vs. Case Temperature

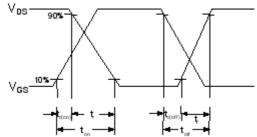
**Figure 11. Transient Thermal Response Curve** 

### **Gate Charge Test Circuit & Waveform**

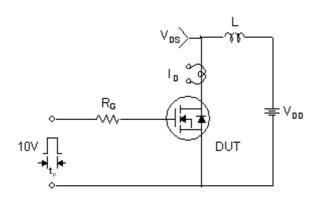


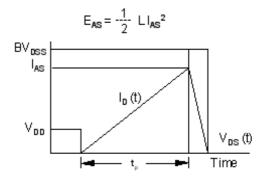
### **Resistive Switching Test Circuit & Waveforms**



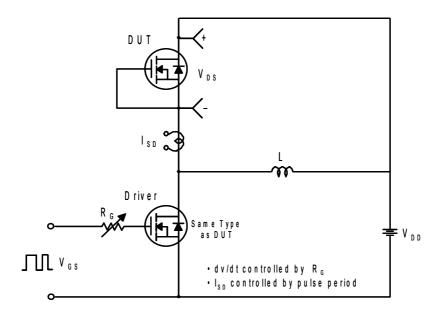


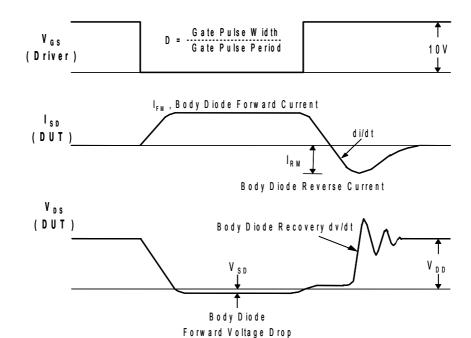
### **Unclamped Inductive Switching Test Circuit & Waveforms**





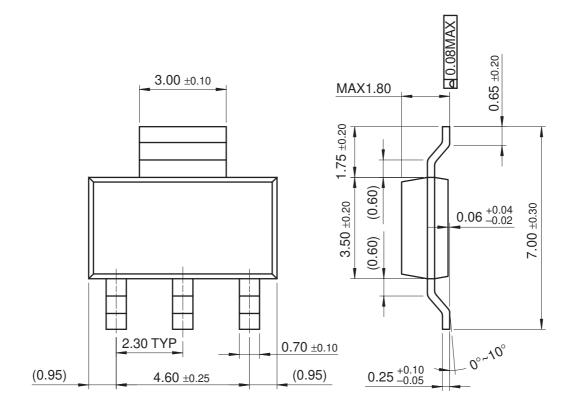
### Peak Diode Recovery dv/dt Test Circuit & Waveforms

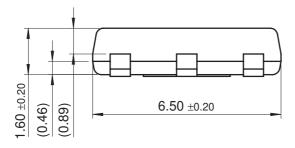




### **Mechanical Dimensions**

# **SOT-223**





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